

GSM2165JZF

20V P-Channel MOSFETs

Product Description

These P-Channel enhancement mode power field effect transistors are using trench DMOS technology. This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode.

These devices are well suited for high efficiency fast switching applications.

Features

- -20V, -4.1A, $R_{DS(ON)}=65m\Omega @ V_{GS}=-4.5V$
- Improved dv/dt capability
- Fast switching
- Suit for -1.8V Gate Drive Applications
- Green Device Available
- SOT-23 package design

Applications

- Notebook
- Load Switch
- Hand-held Instruments

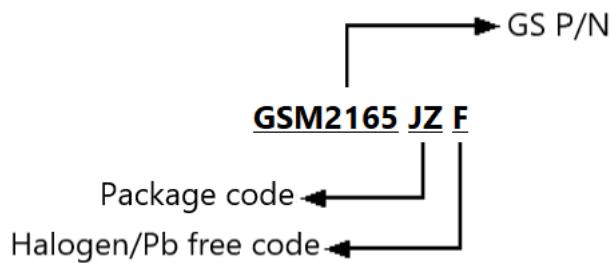
Packages & Pin Assignments

| GSM2165JZF (SOT-23) | |
|---------------------|-------------|
| Pin | Description |
| 1 | Gate |
| 2 | Source |
| 3 | Drain |

Top Views

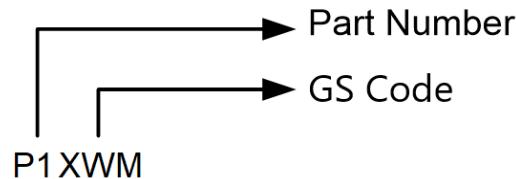
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graph TD; G((G)) --> D((D)); S((S)) --- D; D --- D_D(( ));
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Ordering Information



| Part Number | Package | Quantity Reel |
|-------------|---------|---------------|
| GSM2165JZF | SOT-23 | 3000 PCS |

Marking Information



Absolute Maximum Ratings

T_c=25°C Unless otherwise noted

| Symbol | Parameter | Typical | Unit |
|------------------|--|--|------|
| V _{DS} | Drain-Source Voltage | -20 | V |
| V _{GS} | Gate-Source Voltage | ±12 | V |
| I _D | Continuous Drain Current | $T_A=25^\circ\text{C}$ $T_A=70^\circ\text{C}$ | A |
| I _{DM} | Pulsed Drain Current ¹ | -16.4 | A |
| P _D | Power Dissipation ($T_A=25^\circ\text{C}$) | 1.56 | W |
| | Power Dissipation (Derate above 25°C) | 0.012 | W/°C |
| T _J | Operating Junction Temperature Range | -55 to +150 | °C |
| T _{STG} | Storage Temperature Range | -55 to +150 | °C |
| R _{θJA} | Thermal Resistance-Junction to Ambient | 80 | °C/W |

Electrical Characteristics

$T_J=25^\circ\text{C}$ unless otherwise noted

| Symbol | Parameter | Conditions | Min | Typ | Max | Unit |
|-----------------------------|-----------------------------------|--|------|------|-----------|------------------|
| Static | | | | | | |
| $V_{(\text{BR})\text{DSS}}$ | Drain-Source Breakdown Voltage | $V_{\text{GS}}=0\text{V}, I_D=-250\mu\text{A}$ | -20 | | | V |
| $V_{\text{GS}(\text{th})}$ | Gate Threshold Voltage | $V_{\text{DS}}=V_{\text{GS}}, I_D=-250\mu\text{A}$ | -0.4 | | -0.9 | V |
| I_{GSS} | Gate Leakage Current | $V_{\text{DS}}=0\text{V}, V_{\text{GS}}=\pm 12\text{V}$ | | | ± 100 | nA |
| I_{DSS} | Zero Gate Voltage Drain Current | $V_{\text{DS}}=-20\text{V}, V_{\text{GS}}=0\text{V}$ | | | -1 | μA |
| I_s | Continuous Source Current | $V_G=V_D=0\text{V},$ Force Current | | | -4.1 | A |
| I_{SM} | Pulsed Source Current | | | | -8.2 | |
| $R_{\text{DS}(\text{on})}$ | Drain-Source On-Resistance | $V_{\text{GS}}=-4.5\text{V}, I_D=-4.5\text{A}$ | 52 | 65 | | |
| | | $V_{\text{GS}}=-2.5\text{V}, I_D=-3\text{A}$ | 73 | 85 | | $\text{m}\Omega$ |
| | | $V_{\text{GS}}=-1.8\text{V}, I_D=-1.5\text{A}$ | 100 | 130 | | |
| g_{FS} | Forward Transconductance | $V_{\text{DS}}=-10\text{V}, I_D=-4.5\text{A}$ | 10 | | | S |
| V_{SD} | Diode Forward Voltage | $V_{\text{GS}}=0\text{V}, I_s=-1\text{A}$ | | | -1 | V |
| Dynamic | | | | | | |
| Q_g | Total Gate Charge ^{2,3} | $V_{\text{DS}}=-10\text{V}, V_{\text{GS}}=-4.5\text{V},$ $I_D=-3\text{A}$ | | 6.4 | 9 | |
| Q_{gs} | Gate-Source Charge ^{2,3} | | | 0.9 | 1 | nC |
| Q_{gd} | Gate-Drain Charge ^{2,3} | | | 1.6 | 3 | |
| C_{iss} | Input Capacitance | $V_{\text{DS}}=-10\text{V}, V_{\text{GS}}=0\text{V},$ $f=1\text{MHz}$ | | 515 | 745 | |
| C_{oss} | Output Capacitance | | | 55 | 80 | pF |
| C_{rss} | Reverse Transfer Capacitance | | | 20 | 30 | |
| $t_{\text{d}(\text{on})}$ | Turn-On Time ^{2,3} | $V_{\text{DD}}=-10\text{V}, I_D=-1\text{A},$ $V_{\text{GS}}=-4.5\text{V}, R_G=25\Omega$ | | 5 | 9 | |
| t_r | | | | 17.4 | 33 | |
| $t_{\text{d}(\text{off})}$ | Turn-Off Time ^{2,3} | | | 40.7 | 80 | |
| t_f | | | | 11.4 | 23 | ns |

Note :

- Repetitive Rating : Pulsed width limited by maximum junction temperature.
- The data tested by pulsed , pulse width $\leq 300\mu\text{s}$, duty cycle $\leq 2\%$.
- Essentially independent of operating temperature.

Typical Performance Characteristics

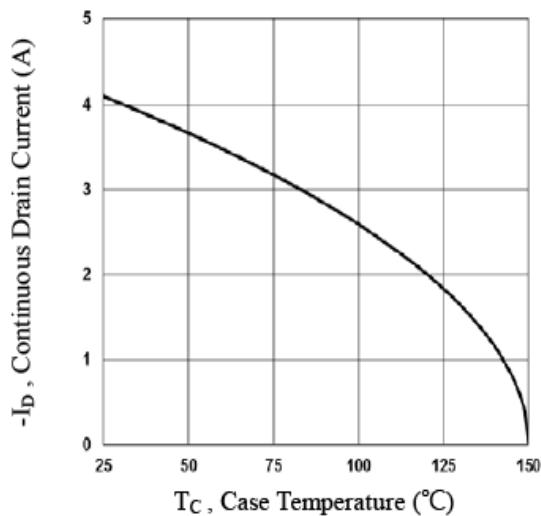


Fig.1 Continuous Drain Current vs T_C

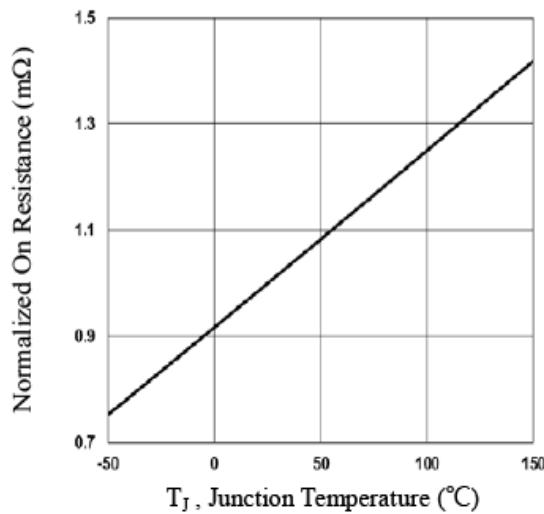


Fig.2 Normalized R_{DSON} vs T_J

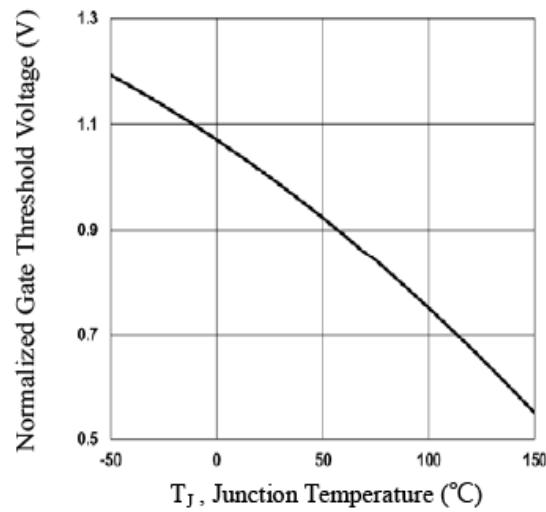


Fig.3 Normalized V_{TH} vs T_J

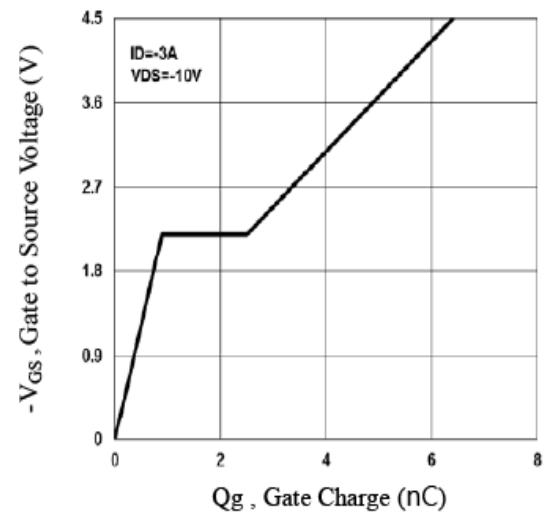


Fig.4 Gate Charge Waveform

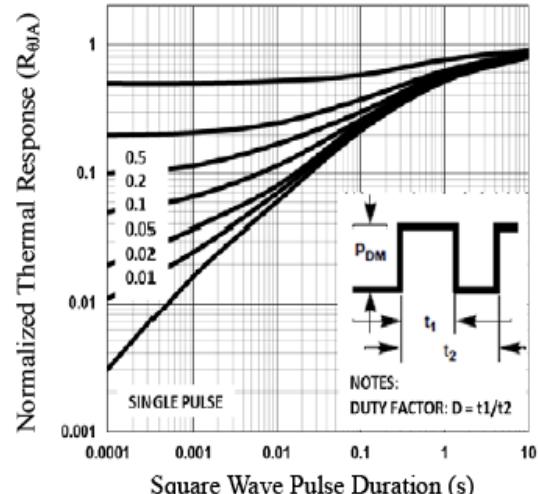


Fig.5 Normalized Transient Impedance

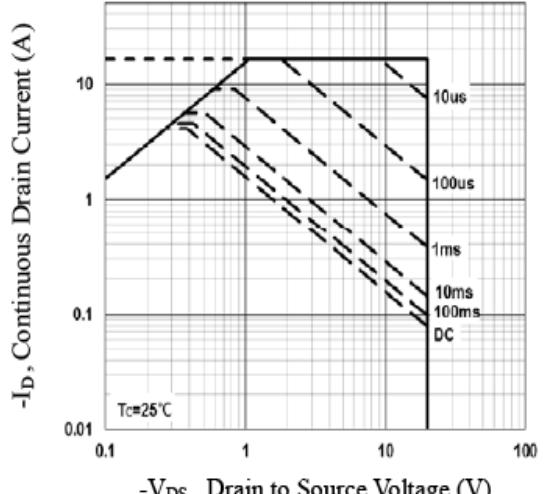
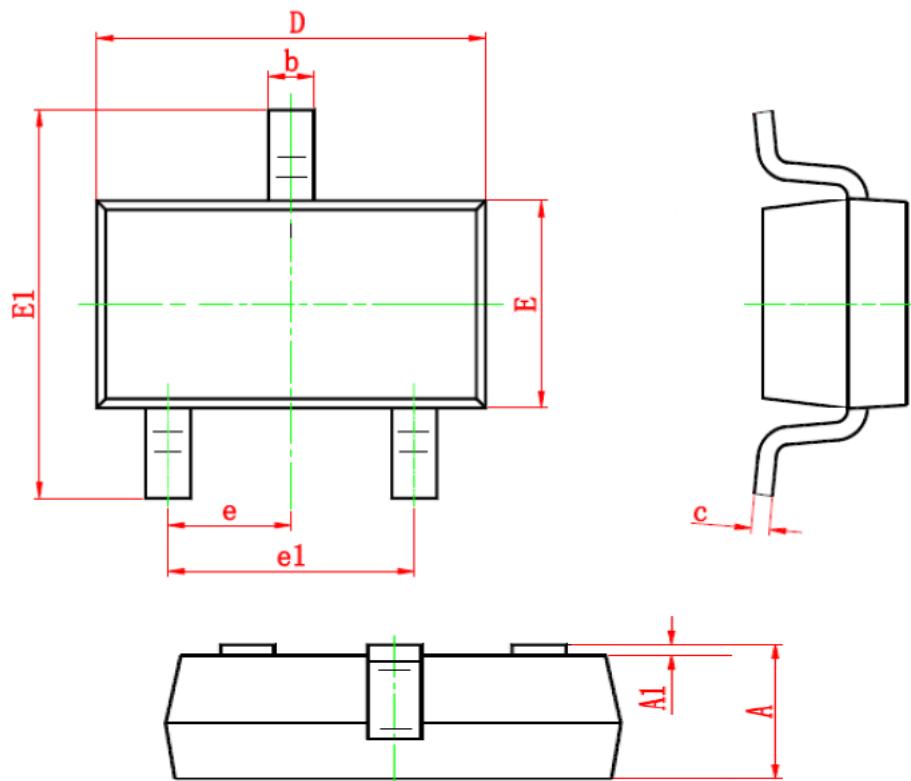


Fig.8 Maximum Safe Operating Area

Package Dimension

SOT-23



Dimensions

| SYMBOL | Millimeters | | Inches | |
|--------|-------------|------|--------|-------|
| | MIN | MAX | MIN | MAX |
| A | 0.9 | 1.14 | 0.035 | 0.045 |
| A1 | 0 | 0.14 | 0 | 0.006 |
| b | 0.3 | 0.51 | 0.012 | 0.020 |
| c | 0.07 | 0.18 | 0.003 | 0.007 |
| D | 2.8 | 3.04 | 0.110 | 0.120 |
| E | 1.2 | 1.4 | 0.047 | 0.055 |
| E1 | 2.1 | 2.64 | 0.083 | 0.104 |
| e | 0.95 Typ | | 0.037 | |
| e1 | 1.78 | 2.05 | 0.070 | 0.081 |

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